

## STB7NK80Z, STB7NK80Z-1 STP7NK80ZFP, STP7NK80Z

N-channel 800 V, 1.5 Ω, 5.2 A, TO-220,TO-220FP,D<sup>2</sup>PAK,I<sup>2</sup>PAK
Zener-protected SuperMESH™ Power MOSFET

#### **Features**

Туре	V <sub>DSS</sub> (@Tjmax)	R <sub>DS(on)</sub>	I <sub>D</sub>
STP7NK80Z	V008	< 1.8Ω	5.2A
STP7NK80ZFP	800V	< 1.8Ω	5.2A
STB7NK80Z	800V	< 1.8Ω	5.2A
STB7NK80Z-1	800V	< 1.8Ω	5.2A

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

### **Applications**

■ Switching application

### **Description**

The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage Power MOSFETs including revolutionary MDmesh™ products.

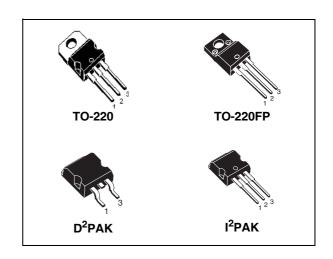


Figure 1. Internal schematic diagram

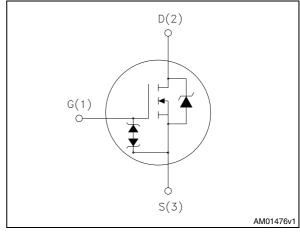


Table 1. Device summary

Order codes	Marking	Package	Packaging
STB7NK80ZT4	B7NK80Z	D²PAK	Tape e reel
STB7NK80Z-1	B7NK80Z	I <sup>2</sup> PAK	
STP7NK80Z	P7NK80Z	TO-220	Tube
STP7NK80ZFP	P7NK80ZFP	TO-220FP	

## **Contents**

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## 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Symbol Parameter -		D <sup>2</sup> PAK	I <sup>2</sup> PAK	TO-220FP	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)		8	00		V
V <sub>GS</sub>	Gate- source voltage		±	30		V
I <sub>D</sub>	Drain current (continuous) at $T_C = 25$ °C		5.2		5.2 <sup>(1)</sup>	Α
I <sub>D</sub>	Drain current (continuous) at $T_C = 100$ °C		3.3		3.3 <sup>(1)</sup>	Α
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)		20.8		20.8 <sup>(1)</sup>	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25°C		125		30	W
	Derating factor		1		0.24	W/°C
V <sub>ESD(G-S)</sub>	Gate source ESD (HBM-C=100 pF, R=1.5 kΩ)		40	000		V
dv/dt (3)	Peak diode recovery voltage slope		4	1.5		V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s; T <sub>C</sub> = 25 °C)				2500	٧
T <sub>j</sub> T <sub>stg</sub>	Max operating junction temperature Storage temperature		-55 1	to 150		°C °C

- 1. Limited only by maximum temperature allowed
- 2. Pulse width limited by safe operating area
- 3.  $I_{SD} \leq$  5.2 A, di/dt  $\leq$  200 A/ $\mu$ s,  $V_{DD} \leq$   $V_{(BR)DSS}$ ,  $T_{j} \leq$   $T_{JMAX}$ .

Table 3. Thermal data

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Symbol	Parameter	TO-220	D <sup>2</sup> PAK	I <sup>2</sup> PAK	TO-220FP	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max		1		4.2	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max		6	62.5		°C/W
T <sub>I</sub>	Maximum lead temperature for soldering purpose		;	300		°C

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj Max)	5.2	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	210	mJ

## 2 Electrical characteristics

(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown voltage	I <sub>D</sub> =1 mA, V <sub>GS</sub> = 0	800			V
I <sub>DSS</sub>	Zero gate voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS}$ = Max rating $V_{DS}$ = Max rating, $T_{C}$ = 125 °C			1 50	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate-body leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			± 10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	3	3.75	4.5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 2.6 \text{ A}$		1.5	1.8	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	$V_{DS} = 15 \text{ V}, I_D = 2.6 \text{ A}$	-	5		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	ı	1138 122 25		pF pF pF
C <sub>oss eq.</sub>	Equivalent output capacitance	V <sub>DS</sub> =0 , V <sub>DS</sub> = 0 to 640 V	-	50		pF
t <sub>d(on)</sub> t <sub>r</sub> t <sub>r(off)</sub> t <sub>r</sub>	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 400 \text{ V}, I_{D} = 2.6 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 17</i> )	-	20 12 45 20		ns ns ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 640 \text{ V}, I_{D} = 5.2 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 18</i> )	-	40 7 21	56	nC nC nC
t <sub>r(Voff)</sub> t <sub>r</sub> t <sub>c</sub>	Off-voltage rise time Fall time Cross-over time	$V_{DD} = 640 \text{ V}, I_D = 5.2 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 17)	-	12 10 20		ns ns ns

<sup>1.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

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<sup>2.</sup>  $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current Source-drain current (pulsed)		-		5.2 20.8	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 5.2 A, V <sub>GS</sub> = 0	-		1.6	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 5.2 \text{ A, di/dt} = 100$ A/ $\mu$ s $V_{DD} = 50 \text{ V, Tj} = 150 ^{\circ}\text{C}$ (see <i>Figure 22</i> )	-	530 3.31 12.5		ns μC Α

- 1. Pulsed: pulse duration=300µs, duty cycle 1.5%
- 2. Pulse width limited by safe operating area

Table 8. Gate-source zener diode

Symbo	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV <sub>GSO</sub>	Gate-source breakdown voltage	I <sub>GS</sub> = ± 1mA (open drain)	30			V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220,  $D^2PAK$ ,  $I^2PAK$  Figure 3. Thermal impedance for TO-220,  $D^2PAK$ ,  $I^2PAK$ 

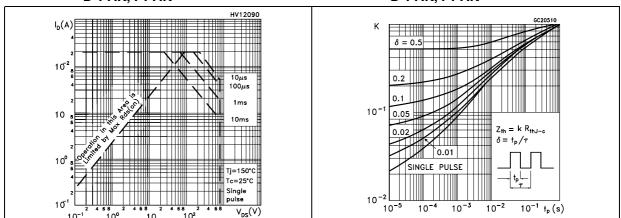


Figure 4. Safe operating area for TO-220FP Figure 5. Thermal impedance for TO-220FP

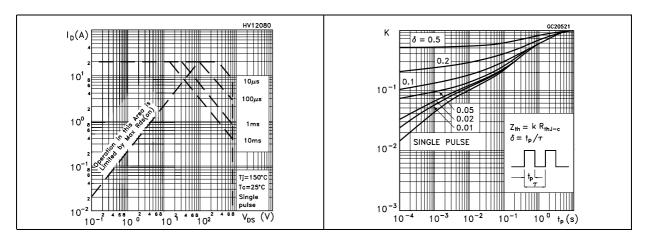
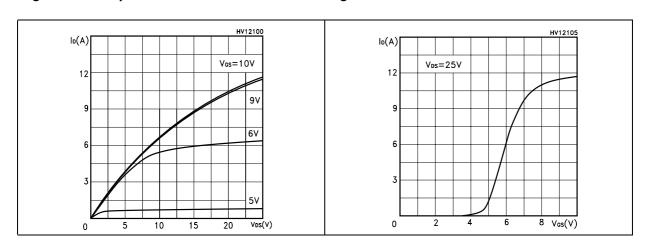


Figure 6. Output characteristics

Figure 7. Transfer characteristics



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Figure 8. Transconductance

Figure 9. Static drain-source on resistance

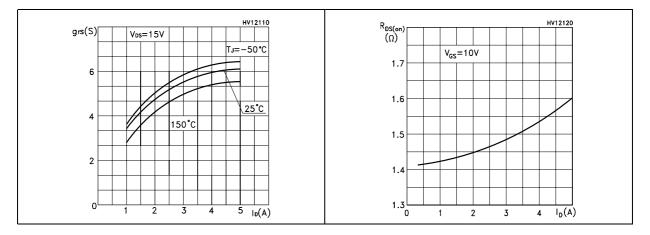


Figure 10. Gate charge vs gate-source voltage Figure 11. Capacitance variations

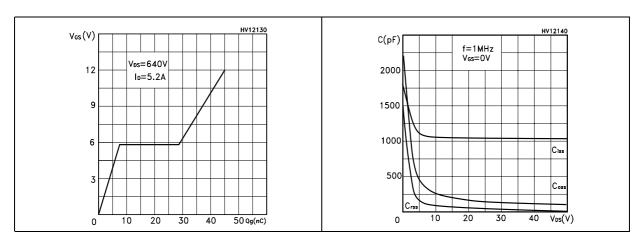


Figure 12. Normalized gate threshold voltage Figure 13. Normalized on resistance vs vs temperature temperature

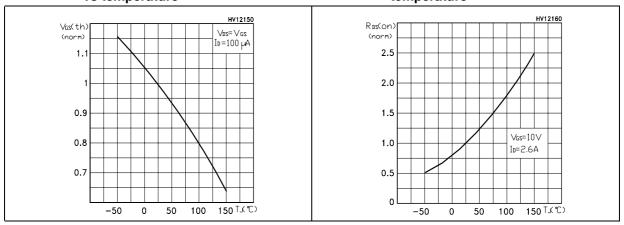
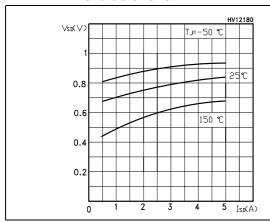


Figure 14. Source-drain diode forward characteristic

Figure 15. Normalized BVDSS vs temperature



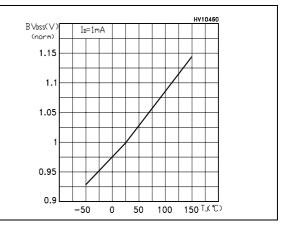
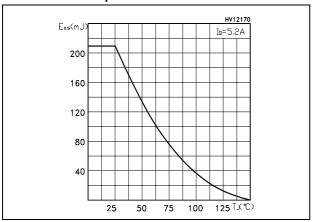


Figure 16. Maximum avalanche energy vs temperature



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### 3 Test circuits

Figure 17. Switching times test circuit for resistive load

Figure 18. Gate charge test circuit

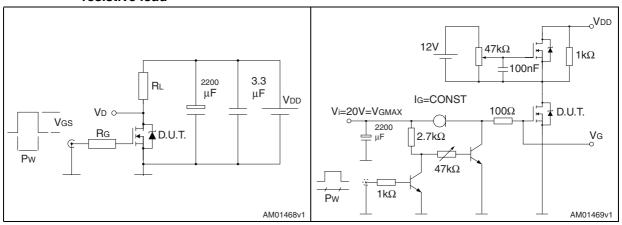


Figure 19. Test circuit for inductive load switching and diode recovery times

Figure 20. Unclamped inductive load test circuit

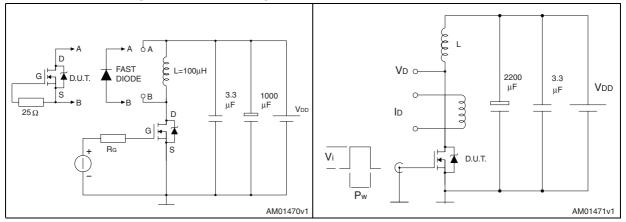
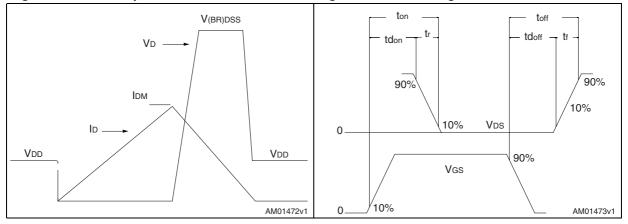


Figure 21. Unclamped inductive waveform

Figure 22. Switching time waveform



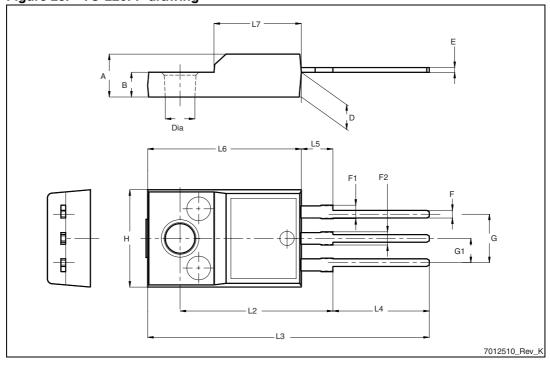
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 9. TO-220FP mechanical data

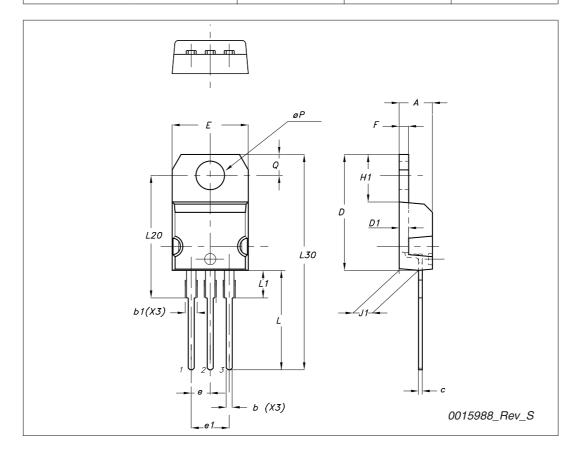
Dim		mm	
Dim.	Min.	Тур.	Max.
Α	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

Figure 23. TO-220FP drawing



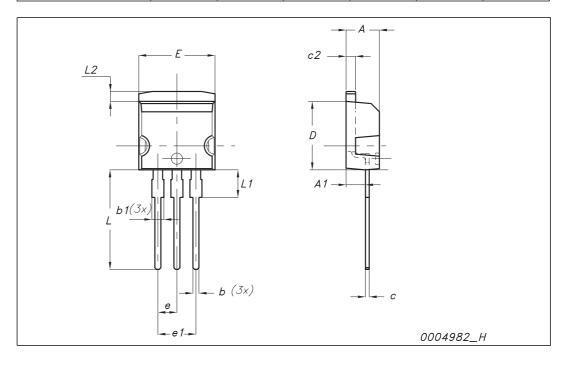
#### TO-220 type A mechanical data

Dim		mm	
	Min	Тур	Max
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
С	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95



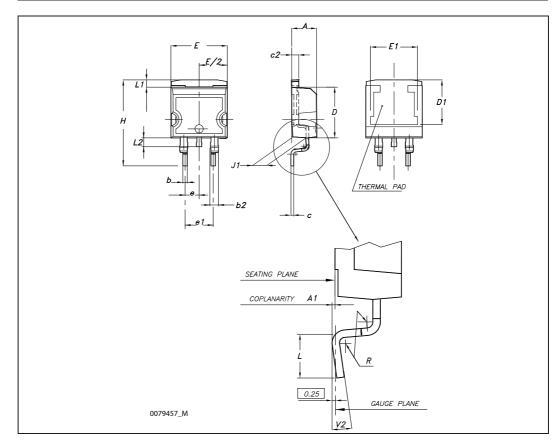
#### I<sup>2</sup>PAK (TO-262) mechanical data

Dim	mm			inch		
	Min	Тур	Max	Min	Тур	Max
A	4.40		4.60	0.173		0.181
A1	2.40		2.72	0.094		0.107
b	0.61		0.88	0.024		0.034
b1	1.14		1.70	0.044		0.066
С	0.49		0.70	0.019		0.027
c2	1.23		1.32	0.048		0.052
D	8.95		9.35	0.352		0.368
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
E	10		10.40	0.393		0.410
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L2	1.27		1.40	0.050		0.055



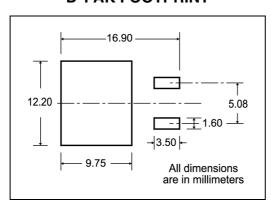
#### D<sup>2</sup>PAK (TO-263) mechanical data

Dim		mm			inch		
	Min	Тур	Max	Min	Тур	Max	
Α	4.40		4.60	0.173		0.181	
A1	0.03		0.23	0.001		0.009	
b	0.70		0.93	0.027		0.037	
b2	1.14		1.70	0.045		0.067	
С	0.45		0.60	0.017		0.024	
c2	1.23		1.36	0.048		0.053	
D	8.95		9.35	0.352		0.368	
D1	7.50			0.295			
E	10		10.40	0.394		0.409	
E1	8.50			0.334			
е		2.54			0.1		
e1	4.88		5.28	0.192		0.208	
Н	15		15.85	0.590		0.624	
J1	2.49		2.69	0.099		0.106	
L	2.29		2.79	0.090		0.110	
L1	1.27		1.40	0.05		0.055	
L2	1.30		1.75	0.051		0.069	
R		0.4			0.016		
V2	0°		8°	0°		8°	

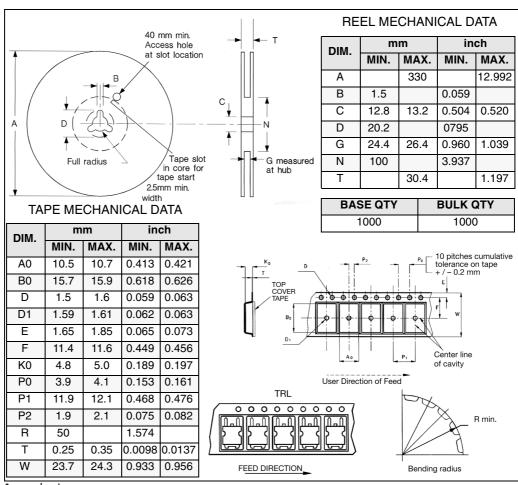


## 5 Packaging mechanical data

### D<sup>2</sup>PAK FOOTPRINT



#### TAPE AND REEL SHIPMENT



# 6 Revision history

Table 10. Revision history

Date	Revision	Changes	
09-Sep-2004	3	Complete version	
16-Aug-2006	4	New template, no content change	
09-Oct-2006	5	Corrected order code	
28-Mar-2010	6	Corrected Table 1: Device summary	

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